

## ABSTRACT

A testing apparatus, by which an optical system to  
5 irradiate a test light to a solid-state imaging device is  
easily aligned with the solid-state imaging device and  
highly efficient tests can be conducted, is provided.

It includes an optical module 35 for irradiating a  
light from a light source to a light receiving surface of  
10 the solid-state imaging device through a pin hole, a  
probe card 20 having contact probes for contacting pads  
of the solid-state imaging device, and a motor 30 and a  
holding arm 31 for moving the optical module 35 to a  
predetermined position corresponding to the solid-state  
15 imaging device to be tested through an opening 20h  
provided to the probe card 20 in a state where the  
contact probes 21 contact the pads of the solid-state  
imaging device to be tested.